

Machine Learning and Data Mining

VC Dimension

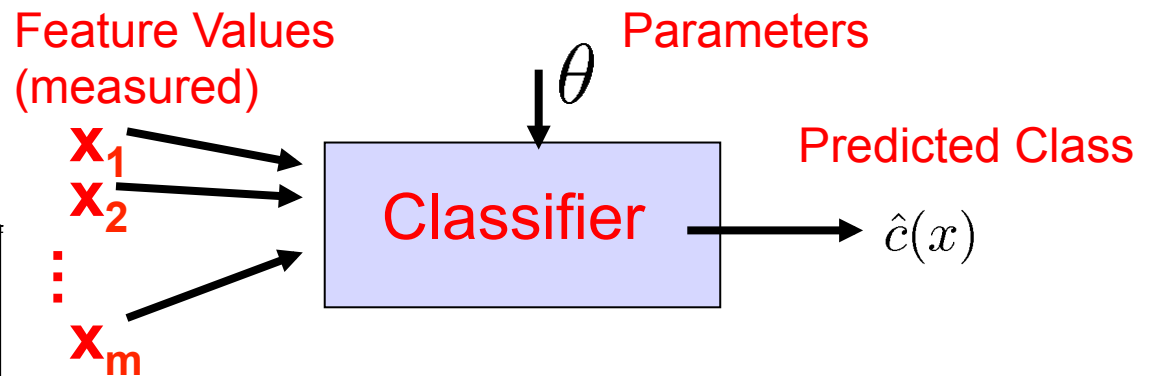
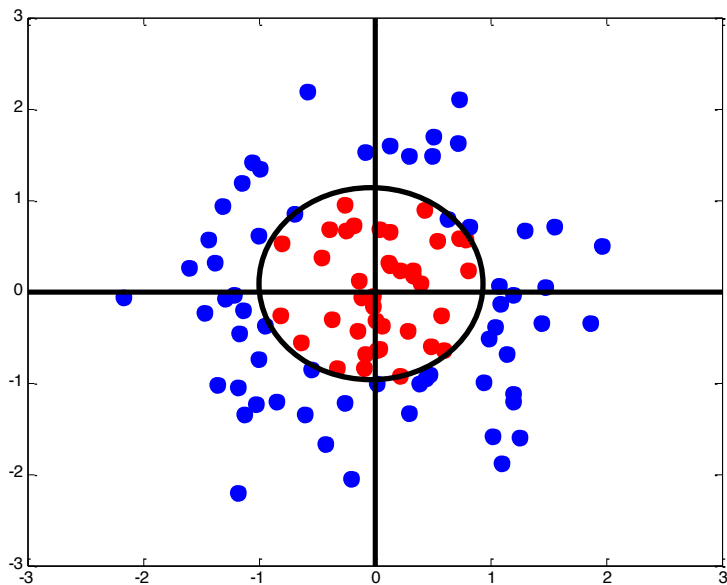
Prof. Alexander Ihler
Fall 2012



Slides based on Andrew Moore's

Learners and Complexity

- We've seen many versions of underfit/overfit trade-off
 - Complexity of the learner
 - “Representational Power”
- Different learners have different power

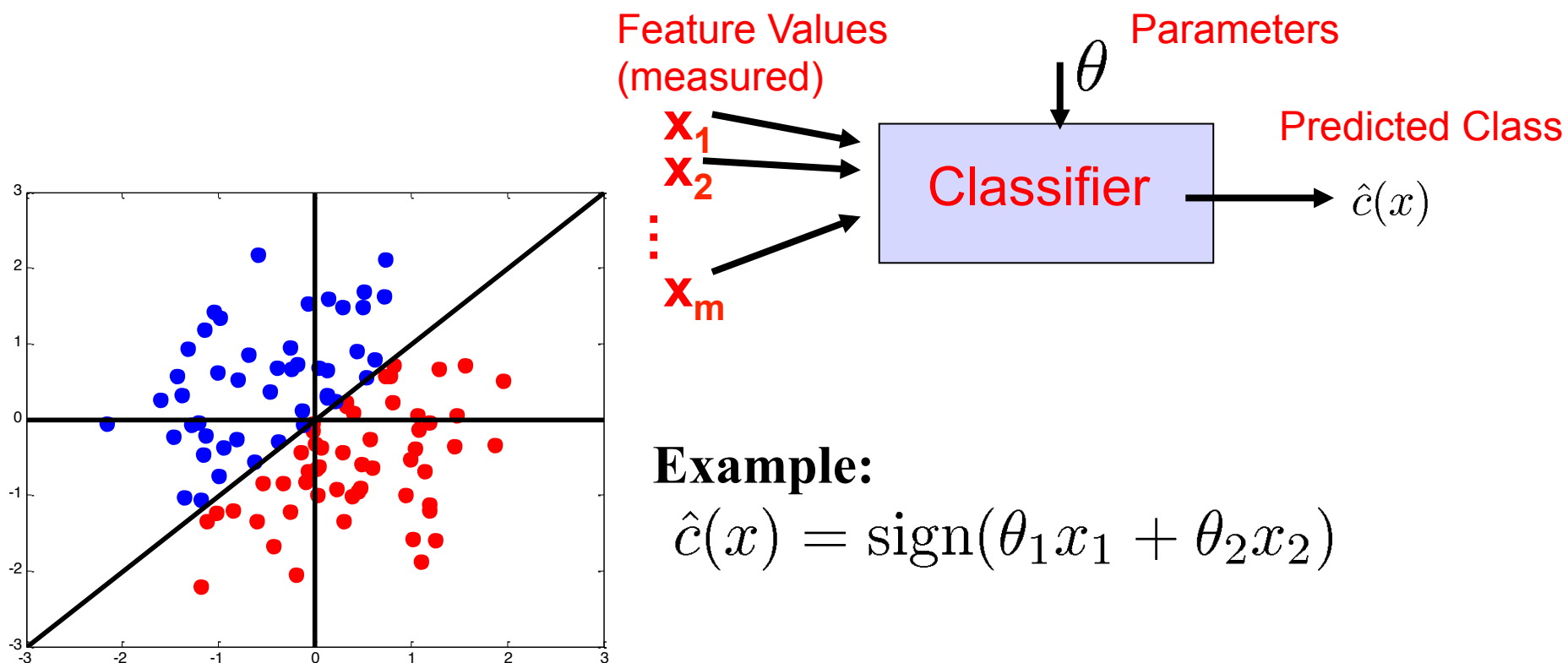


Example:

$$\hat{c}(x) = \text{sign}(x^T x - \theta_0)$$

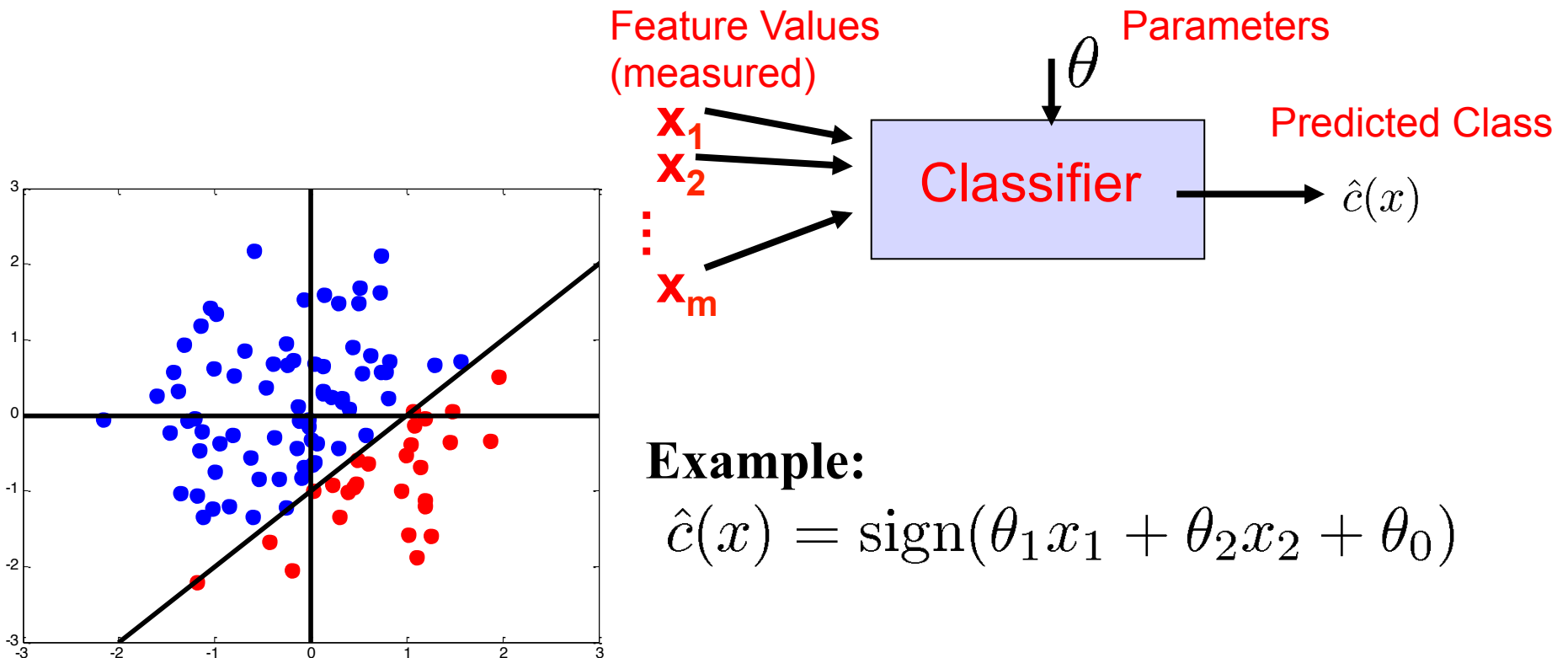
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Learners and Complexity

- We've seen many versions of underfit/overfit trade-off
 - Complexity of the learner
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- Different learners have different power
- Usual trade-off:
 - More power = represent more complex systems, might overfit
 - Less power = won't overfit, but may not find “best” learner
- How can we quantify representational power?
 - Not easily...
 - One solution is VC (Vapnik-Chervonenkis) dimension

Some notation

- Let's assume our training data are iid from some distribution $p(x)$
- Define “risk” and “empirical risk”
 - These are just “long term” test and observed training error

$$R(\theta) = \text{TestError} = \mathbb{E}[\delta(c \neq \hat{c}(x; \theta))]$$

$$R^{\text{emp}}(\theta) = \text{TrainError} = \frac{1}{N} \sum_i \delta(c^{(i)} \neq \hat{c}(x^{(i)}; \theta))$$

- How are these related? Depends on overfitting...
 - Underfitting domain: pretty similar...
 - Overfitting domain: test error might be lots worse!

VC Dimension and Risk

- Given some classifier, let H be its VC dimension
 - Represents “representational power” of classifier

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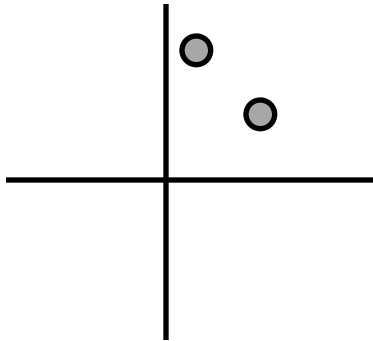
$$R^{\text{emp}}(\theta) = \text{TrainError} = \frac{1}{N} \sum_i \delta(c^{(i)} \neq \hat{c}(x^{(i)}; \theta))$$

- With “high probability” $(1-\eta)$, Vapnik showed

$$\text{TestError} \leq \text{TrainError} + \sqrt{\frac{H \log(2N/H) + H - \log(\eta/4)}{N}}$$

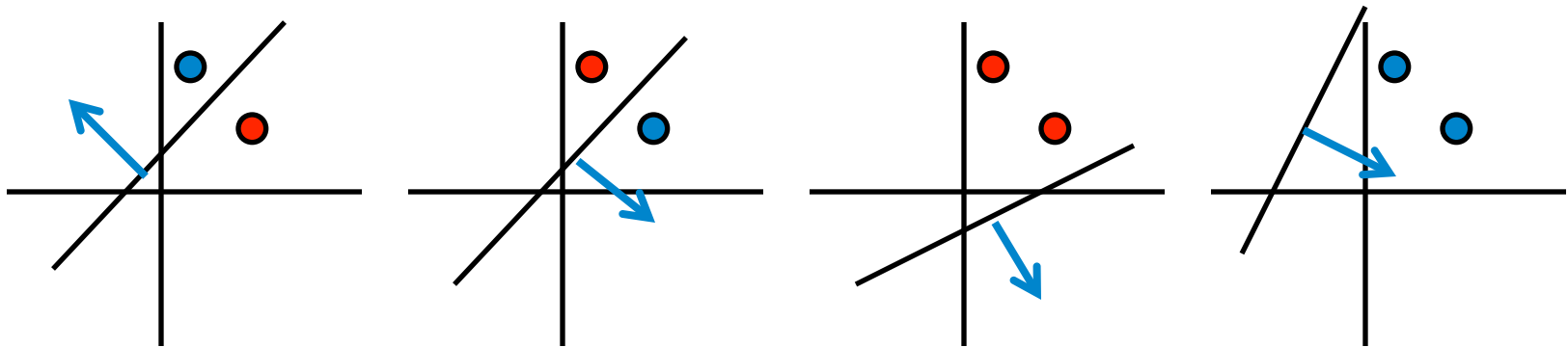
Shattering

- We say a classifier $f(x)$ can shatter points $x_1 \dots x_N$ iff
For *all* $y_1 \dots y_N$, $f(x)$ can achieve zero error on
training data $(x_1, y_1), (x_2, y_2), \dots (x_N, y_N)$
(i.e., there exists some θ that gets zero error)
- Can $f(x; \theta) = \text{sign}(\theta x^T)$ shatter these points?



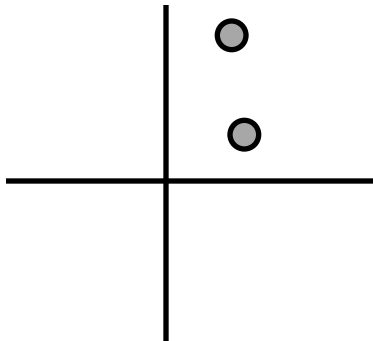
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- Can $f(x; \theta) = \text{sign}(\theta_0 + \theta_1 x_1 + \theta_2 x_2)$ shatter these points?
- Yes: there are 4 possible training sets...



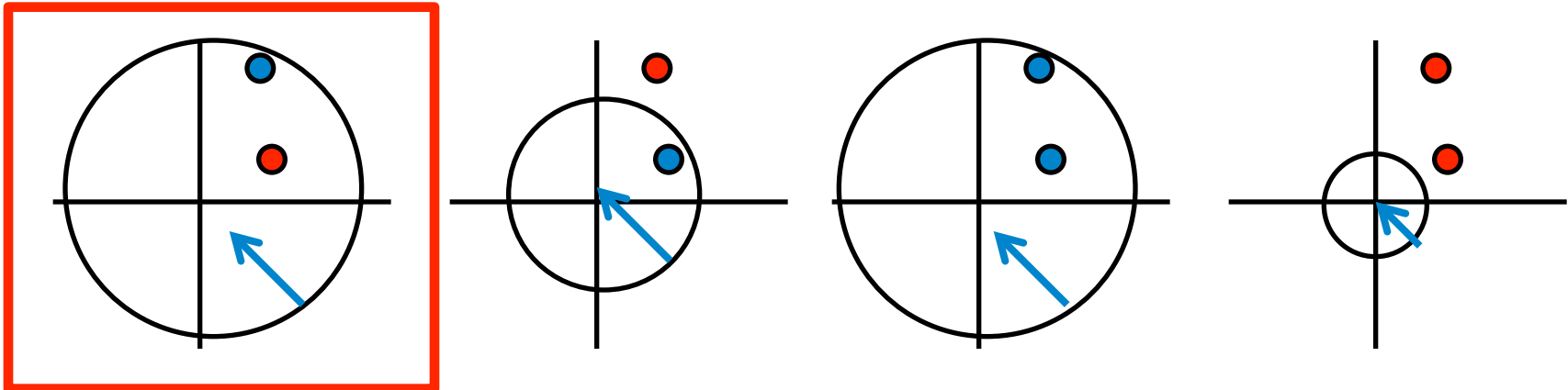
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- Nope!

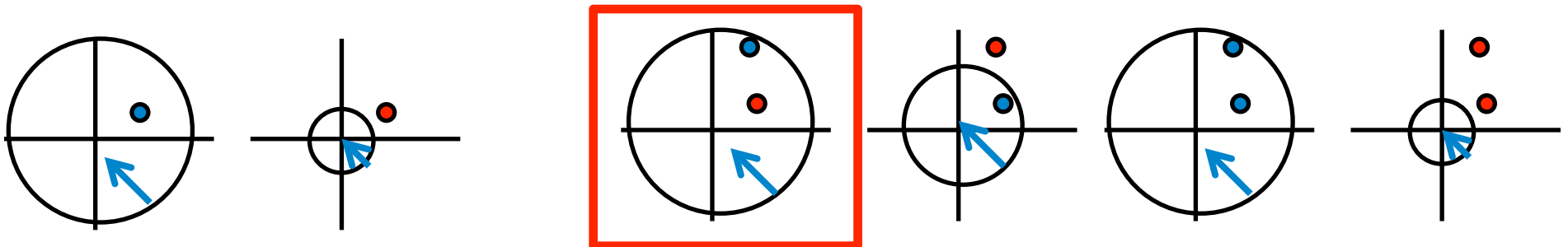


VC Dimension

- The VC dimension is defined as
The maximum number of points that *can be arranged*
so that $f(x)$ can shatter them
- Example: what's the VC dimension of the (zero-centered) circle, $f(x; \theta) = \text{sign}(x^T x + \theta)$?

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- VCdim = 1 : can arrange one point, cannot arrange two (previous example was general)

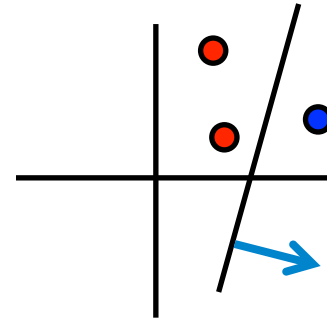


VC Dimension

- Example: what's the VC dimension of the two-dimensional line, $f(x;\theta) = \text{sign}(\theta_1 x_1 + \theta_2 x_2 + \theta_0)$?

VC Dimension

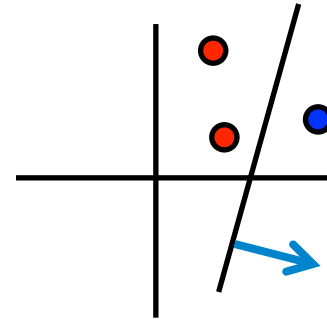
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- VC dim ≥ 3 ? Yes



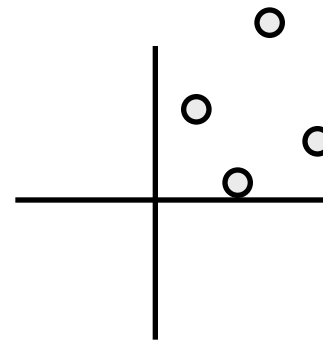
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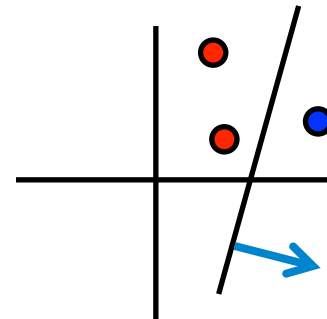


- VC dim ≥ 4 ?



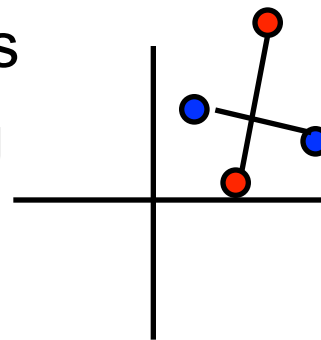
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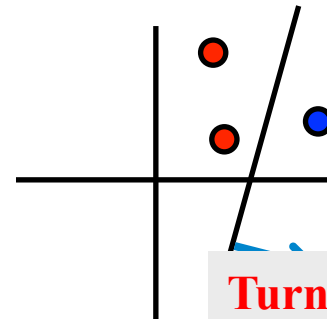
- VC dim ≥ 4 ? No...

Any line through these points must split one pair (by crossing one of the lines)

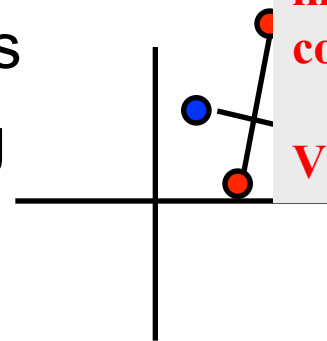


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Turns out:
For a general, linear
classifier (perceptron)
in d dimensions with a
constant term:

VC dim = d+1

VC dimension

- VC dimension measures the “power” of the learner
- Does *not* necessarily equal the # of parameters!
- Number of parameters does not necessarily equal complexity
 - Can define a classifier with a lot of parameters but not much power (how?)
 - Can define a classifier with one parameter but lots of power (how?)
- Lots of work to determine what the VC dimension of various learners is...

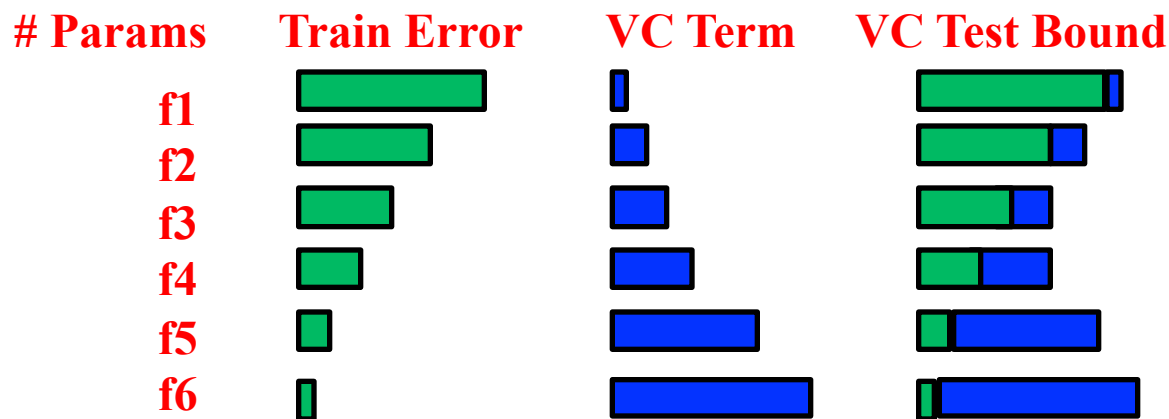
Using VC dimension

- Recall how we used validation data, or cross-validation error rates to select a complexity



Using VC dimension

- Recall how we used validation data, or cross-validation error rates to select a complexity
- Use VC dimension based bound on test error similarly
- “Structural Risk Minimization” (SRM)



Using VC dimension

- Recall how we used validation data, or cross-validation error rates to select a complexity
- Use VC dimension based bound on test error similarly
- Other Alternatives
 - Probabilistic models: likelihood under model (rather than classification error)
 - AIC (Aikike Information Criterion)
 - Log-likelihood of training data - # of parameters
 - BIC (Bayesian Information Criterion)
 - Log-likelihood of training data - (# of parameters)*log(N)
- Similar to VC dimension: performance + penalty
- BIC conservative; SRM very conservative
- Also, “true Bayesian” methods (take prob. learning...)